Supporting Information

Red-Emitting Cs₂NaScCl₆:Sm Flexible Films for High-Resolution X-Ray Imaging

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Figure S1. Physical diagram of Cs₂NaScCl₆.



Figure S2. PXRD of $Cs_2NaScCl_6$ compared to the simulated pattern based on SCXRD measurements. It shows that the synthesized material is pure phase, and verifies the accuracy of single crystal data.



Figure S3. PXRD patterns of Cs₂NaScCl₆ and Cs₂NaScCl₆:7%Sm crystal powder

exposed to ambient air.



Figure S4. TG and DTA curves of Cs₂NaScCl₆ (left), Cs₂NaScCl₆:7%Sm (right).



Figure S5. The band gap fitting diagram of Cs₂NaScCl₆ and Cs₂NaScCl₆:7%Sm.

Attenuation efficiency T is defined as:

 $T = 1 - e^{-\mu_L x}$

In this equation, μ_L is the linear attenuation coefficient which can be obtained by $\rho_{\mu m}$, x is the effective retarding thickness, ρ is the density of materials and μ_m is the mass attenuation coefficient. The value of μ_m was easily obtained from the photon cross sections database XCOM.



Figure S6. X-ray absorption coefficient spectra of $Cs_2NaScCl_6$ and other scintillating materials.



Figure S7. XEL diagram of BGO, Cs₂NaScCl₆, and Cs₂NaScCl₆:7%Sm at 50kV with different tube currents.

The light yield of $Cs_2NaScCl_6$:7%Sm was calculated with BGO's optical yield of 100.0% as the standard. We measured the response amplitude (R) of the BGO and $Cs_2NaScCl_6$:7%Sm using photo-multiplier tubes (PMT R928). LY is obtained from the following equation:

$$\frac{LY_{sample}}{LY_{BGO}} = \frac{R_{sample}}{R_{BGO}} \times \frac{\int I_{BGO}S(\lambda)d\lambda / \int I_{BGO}d\lambda}{\int I_{sample}S(\lambda)d\lambda / \int I_{sample}d\lambda}$$

where $I(\lambda)$ is the XEL spectrum and $S(\lambda)$ in Figure S8 is the detection efficiency of the PMT.



Figure S8. The detection efficiency of PMT.



Figure S9. Detection limit test diagram of BGO, Cs₂NaScCl₆, and Cs₂NaScCl₆:7%Sm at different tube currents at 50 kV.



Figure S10. Physical images of Cs₂NaScCl₆:7%Sm and Cs₂NaScCl₆:10%Tb under 254

nm lamp irradiation in a UV dark box.



Figure S11. CIE chromaticity diagrams corresponding to X-ray luminescence for Cs₂NaScCl₆, Cs₂NaScCl₆:xSm, Cs₂NaScCl₆:yTb, and Cs₂NaScCl₆:xSm,yTb sample powders.



Figure S12. Photographs of Cs₂NaScCl₆:7%Sm and other flexible scintillation films.



Figure S13. Physical and X-imaging of wire-pair card by Cs₂NaScCl₆:7%Sm scintillating film under 8.154 mGyair s⁻¹ X-ray irradiation.



Figure S14. X-ray imaging of $Cs_2NaScCl_6$, $Cs_2NaScCl_6$:10%Tb and $Cs_2NaScCl_6$:0.2%Sm,1%Tb scintillation film pairs of 20 line pairs of standard line pairs and corresponding MTF curves.